Hi Sreenivasa and Prashant,

I've attempted to connect to the WKUP_RFSS0 core with no success.

I'm using a LP-XDS110 debug adapter.

After replacing the on-target JTAG_TRSTn PD with a PU (to let JTAG out of reset), I am able to run the Test Connections option within the CCS Target Configuration dialog.

This indicates a working JTAG chain.

Test Connections output -

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-----[Print the board config pathname(s)]---------------------------------

C:\Users\bhodgins\AppData\Local\TEXASI~1\
CCS\ccs2041\0\0\BrdDat\testBoard.dat

-----[Print the reset-command software log-file]-----------------------------

This utility has selected a 100/110/510 class product.
This utility will load the adapter 'jioxds110.dll'.
The library build date was 'Jan 9 2026'.
The library build time was '14:41:05'.
The library package version is '20.4.0.3835'.
The library component version is '35.35.0.0'.
The controller does not use a programmable FPGA.
The controller has a version number of '5' (0x00000005).
The controller has an insertion length of '0' (0x00000000).
This utility will attempt to reset the controller.
This utility has successfully reset the controller.

-----[Print the reset-command hardware log-file]-----------------------------

The scan-path will be reset by toggling the JTAG TRST signal.
The controller is the XDS110 with USB interface.
The link from controller to target is direct (without cable).
The software is configured for XDS110 features.
The controller cannot monitor the value on the EMU[0] pin.
The controller cannot monitor the value on the EMU[1] pin.
The controller cannot control the timing on output pins.
The controller cannot control the timing on input pins.
The scan-path link-delay has been set to exactly '0' (0x0000).

-----[Perform the Integrity scan-test on the JTAG IR]------------------------

This test will use blocks of 64 32-bit words.
This test will be applied just once.

Do a test using 0xFFFFFFFF.
Scan tests: 1, skipped: 0, failed: 0 Do a test using 0x00000000.
Scan tests: 2, skipped: 0, failed: 0
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Do a test using 0xFE03E0E2.
Scan tests: 3, skipped: 0, failed: 0
Do a test using 0x01FC1F1D.
Scan tests: 4, skipped: 0, failed: 0
Do a test using 0x5533CCAA.
Scan tests: 5, skipped: 0, failed: 0
Do a test using 0xAACC3355.
Scan tests: 6, skipped: 0, failed: 0
All of the values were scanned correctly.

The JTAG IR Integrity scan-test has succeeded.

-----[Perform the Integrity scan-test on the JTAG DR]-----------------------

This test will use blocks of 64 32-bit words.
This test will be applied just once.

Do a test using 0xFFFFFFFF.
Scan tests: 1, skipped: 0, failed: 0
Do a test using 0x00000000.
Scan tests: 2, skipped: 0, failed: 0
Do a test using 0xFE03E0E2.
Scan tests: 3, skipped: 0, failed: 0
Do a test using 0x01FC1F1D.
Scan tests: 4, skipped: 0, failed: 0
Do a test using 0x5533CCAA.
Scan tests: 5, skipped: 0, failed: 0
Do a test using 0xAACC3355.
Scan tests: 6, skipped: 0, failed: 0 All of the values were scanned
correctly.

The JTAG DR Integrity scan-test has succeeded.

Attempting to connect to the WKUP_Cortex_R5_0 fails with code -1170


Error connecting to the target: (Error -1170 @ 0x0) Unable to access the DAP.
Reset the device, and retry the operation. If error persists, confirm
configuration, power-cycle the board, and/or try more reliable JTAG settings
(e.g. lower TCLK). (Emulation package 20.4.0.3835)

As another easy test, I held MCU_RESETz low while attempting a connect.

Texas Instruments XDS110 USB Debug Probe/WKUP_Cortex_R5_0 Error connecting to
the target: (Error -6310) PRSC module failed to read a register. (Emulation
package 20.4.0.3835)

A final test was to connect JTAG_TRSTn to MCU_RESETz for XDS110 timed
assertion of the reset signal.

Same error

Texas Instruments XDS110 USB Debug Probe/WKUP_Cortex_R5_0 Error connecting to
the target: (Error -6310) PRSC module failed to read a register. (Emulation
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package 20.4.0.3835) It seems while in this warm reset loop state core attachement is not possible.

Bill